Notice of References Cited 10/829,258 Reexamination IMAI ET AL Examiner 6222183Seung C. Sohn Reexamination IMAI ET AL Page 1 of 1

Application/Control No.

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,747,797	05-1998	Fujita, Muneo	250/231.14
	В	US-6,222,183	04-2001	Taniguchi et al.	250/231.13
	С	US-6,232,593	05-2001	Taniguchi et al.	250/231.13
	۵	US-6,255,644	07-2001	Taniguchi et al.	250/231.13
	Е	US-6,713,756	03-2004	Yamamoto et al.	250/231.13
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Р					
	Q					
	R					
	s					
	Т					•.

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	****
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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